

Si4410DY*

Single N-Channel Logic Level PowerTrench MOSFET

General Description

This N-Channel Logic Level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

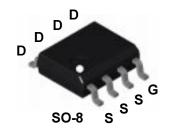
This device is well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

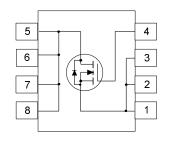
Applications

- · Battery switch
- · Load switch
- Motor controls

Features

- 10 A, 30 V. $R_{DS(ON)} = 0.0135 \Omega @ V_{GS} = 10 V$ $R_{DS(ON)} = 0.020 \Omega @ V_{GS} = 4.5 V$
- · Low gate charge.
- · Fast switching speed.
- High performance trench technology for extremely low $R_{_{\mathrm{DS(ON)}}}.$
- · High power and current handling capability.





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V _{DSS}	Drain-Source Voltage		30	V	
V _{GSS}	Gate-Source Voltage		<u>+</u> 20	V	
I _D	Drain Current - Continuous	(Note 1a)	10	Α	
	- Pulsed		50		
P _D	Power Dissipation for Single Operation	(Note 1a)	2.5	W	
		(Note 1b)	1.2		
		(Note 1c)	1		
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	∘C	

Thermal Characteristics

R _{eJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	∘C/W
R _{eJC}	Thermal Resistance, Junction-to-Case	(Note 1)	25	∘C/W

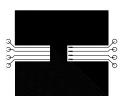
Package Outlines and Ordering Information

Device Marking		Device	Reel Size	Tape Width	Quantity
4410		SI4410DY	13"	12mm	2500 units

^{*} Die and manufacturing source subject to change without prior notification.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	30			٧
$\frac{\Delta BVDSS}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		21		mV/∘C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 30 V, V _{GS} = 0 V V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55∘C			1 25	μA
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu A$	1			V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		-4.5		mV/∘C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}, T_J = 125 ^{\circ}\text{C}$ $V_{GS} = 4.5 \text{ V}, I_D = 8 \text{ A}$		0.011 0.018 0.017	0.0135 0.032 0.020	Ω
I _{D(on)}	On-State Drain Current	V _{GS} = 10 V, V _{DS} = 5 V	20			Α
g FS	Forward Transconductance	V _{DS} = 10 V, I _D = 10 A		27		S
Dynamic	Characteristics		ļ			
C _{iss}	Input Capacitance	V _{DS} = 15 V, V _{GS} = 0 V,		1350		pF
Coss	Output Capacitance	f = 1.0 MHz		340		pF
C _{rss}	Reverse Transfer Capacitance			125		pF
Switchir	ng Characteristics (Note 2)				
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 25 \text{ V}, I_D = 1 \text{ A}, R_L = 25 \Omega$			30	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V, } R_{GEN} = 6 \Omega$			20	ns
t _{d (off)}	Turn-Off Delay Time				100	ns
t _f	Turn-Off Fall Time				80	ns
t _{rr}	Drain-Source Reverse Recovery Time	$I_F = 2.3A$, di/dt = $100A/\mu s$			80	nS
Q_g	Total Gate Charge	V _{DS} = 15 V, I _D = 10 A,		22	60	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		5		nC
Q_{gd}	Gate-Drain Charge			4		nC
Drain-So	ource Diode Characteris	tics and Maximum Ratings				
Is	Maximum Continuous Drain-S				2.3	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 2.3 A (Note 2)		0.7	1.1	V

^{1:} R_{0,J} is the sum of the junction-to-case and case-to-ambient resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 50° C/W when mounted on a 1 in² pad of 2 oz. copper.



b) 105° C/W when mounted on a 0.04 in² pad of 2 oz. copper.



Scale 1 : 1 on letter size paper 2: Pulse Test: Pulse Width \leq 300 $\mu s, \, Duty \, Cycle \leq$ 2.0%

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